Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
09/849,570	ABELARD ET AL	
Examiner	Art Unit	
Thai Tran	2616	

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Class	Subclass	Date	Examiner
386	6-8, 33, 68-70, 81- 82, 111- 112	5/28/2005	πα
375	240.05	5/27/2005	πο
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375	240.12	5/27/2005	πο
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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